NEW

High End model for 3D Confocal Raman & TERS

Nanofinder® HE

Stability
Highest mechanical and thermal stability due to granite frame

Accuracy
Self-calibration with buit-in hollow cathode spectral lamp

Highest sensitivity
High throughput optics, detector QE>90%

High speed 3D mapping
<3 ms/point (simultaneous with AFM)

Easy operation
Automatical signal-to-pinhole alignment

Microscope

▪*Up-right* ▪*Inverted* ▪*Transmission*
Microscope types convertible within *1 second*

Scanner

▪*Piezo-stage* ▪*Step motors* ▪*AFM, etc.*
>10 standard configurations

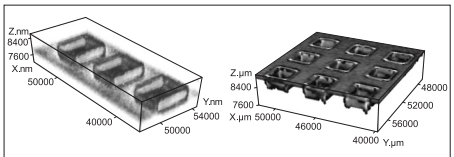
AFM-Raman

One AFM for both:
▪*Reflection & Transmission Confocal Raman-AFM* combined operations
▪*TERS imaging: 50 nm spatial resolution*

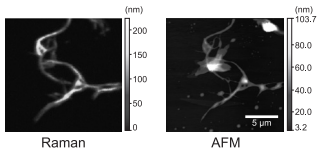
Other features

■ ***All in one*** fully automated device with built-in:
3 lasers + external input; motorized exchangeable optics for UV, VIS, NIR; polarization optics in excitation & detection

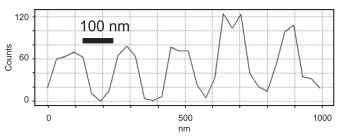
■ Measurement example



3D Raman images of Si devices



SWCNT. Raman and AFM image.



100 nm Line&Space Si/SiO_2 structure. TERS.

■ Typical Specification

Confocal resolution (Laser 473 nm)	Objective 100×0.95 (air)	Objective 150×1.25 (water)
Lateral (X,Y)	<200 nm	<180 nm
Axial (Z)	<500 nm	<400 nm

Spectrometer focal length 550 nm	Grating 1800 G/mm	Echelle Grating 75 G/mm
Spectral resolution	0.77cm^{-1}	0.2cm^{-1}
Spectral accuracy	0.43cm^{-1}	0.1cm^{-1}

(at 550nm)

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